

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	400	(356/450).CCLS.	US-PGPUB; USPAT	OR	OFF	2006/01/17 16:47
L2	54	(356/456).CCLS.	US-PGPUB; USPAT	OR	OFF	2006/01/17 16:47
L3	80	(356/489).CCLS.	US-PGPUB; USPAT	OR	OFF	2006/01/17 16:47
L4	91	(356/495).CCLS.	US-PGPUB; USPAT	OR	OFF	2006/01/17 16:47
L5	215	(356/511).CCLS.	US-PGPUB; USPAT	OR	OFF	2006/01/17 16:47
L6	308	(356/512).CCLS.	US-PGPUB; USPAT	OR	OFF	2006/01/17 16:47
L7	703980	interfer or interfere or interfering or interference or interferometer or interferometric or interferometrically or interferogram	US-PGPUB; USPAT	OR	ON	2006/01/17 16:59
L8	825294	image or imaging or imager	US-PGPUB; USPAT	OR	ON	2006/01/17 17:00
L9	205058	microscope or microscopic or microscopically	US-PGPUB; USPAT	OR	ON	2006/01/17 17:03
L10	1325114	semiconductor or wafer or substrate or mask or die or reticle	US-PGPUB; USPAT	OR	ON	2006/01/17 17:01
L11	160321	L7 and L8	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L12	31461	L11 and L9	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L13	25883	L12 and L10	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L14	750275	align or aligning or aligner or alignment	US-PGPUB; USPAT	OR	ON	2006/01/17 17:00
L15	13230	L13 and L14	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L16	879040	complex or imaginary	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L17	9284	L15 and L16	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L18	1303	"356"/\$.ccls. and L15	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L19	1077	"250"/\$.ccls. and L15	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L20	559	"356"/\$.ccls. and L17	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L21	380	"250"/\$.ccls. and L17	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47

L22	703980	interfer or interfere or interfering or interference or interferometer or interferometric or interferometrically or interferogram	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L23	825294	image or imaging or imager	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L24	205058	microscope or microscopic or microscopically	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L25	1325114	semiconductor or wafer or substrate or mask or die or reticle	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L26	160321	L22 and L23	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L27	31461	L26 and L24	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L28	25883	L27 and L25	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L29	750275	align or aligning or aligner or alignment	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L30	13230	L28 and L29	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L31	879040	complex or imaginary	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L32	9284	L30 and L31	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L33	168	"356"/450-521.ccls. and L32	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L34	3	("4818110" "6078392" "6262818"). PN.	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L35	825294	image or imaging or imager	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L36	750275	align or aligning or aligner or alignment	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L37	912635	detector or sensor or "ccd"	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L38	4579	L35 with L36 with L37	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L39	880	"356"/\$.ccls. and L38	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L40	703980	interfer or interfere or interfering or interference or interferometer or interferometric or interferometrically or interferogram	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L41	1764	L38 and L40	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L42	545	"356"/\$.ccls. and L41	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47

L43	407	"250"/\$.ccls. and L41	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L44	825294	image or imaging or imager	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L45	750275	align or aligning or aligner or alignment	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L46	912635	detector or sensor or "ccd"	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L47	4579	L44 with L45 with L46	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L48	703980	interfer or interfere or interfering or interference or interferometer or interferometric or interferometrically or interferogram	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L49	1764	L47 and L48	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L50	101	"382"/\$.ccls. and L49	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L51	1	("re35350").PN.	US-PGPUB; USPAT	OR	OFF	2006/01/17 16:47
L52	5	("RE35350").URPN.	USPAT	OR	ON	2006/01/17 16:47
L53	6	("5276337").URPN.	USPAT	OR	ON	2006/01/17 16:47
L54	224	linnik	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L55	21	("4732483").URPN.	USPAT	OR	ON	2006/01/17 16:47
L56	58	("5112129").URPN.	USPAT	OR	ON	2006/01/17 16:47
L57	50	("4818110").URPN.	USPAT	OR	ON	2006/01/17 16:47
L58	13	("5112125").URPN.	USPAT	OR	ON	2006/01/17 16:47
L59	97675	magnify or magnification	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L60	825294	image or imaging or imager	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L61	912635	detector or sensor or "ccd"	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L62	4385	L59 with L60 with L61	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L63	451	"382"/\$.ccls. and L62	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L64	614	"356"/\$.ccls. and L62	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L65	734	"250"/\$.ccls. and L62	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47

L66	703980	interfer or interfere or interfering or interference or interferometer or interferometric or interferometrically or interferogram	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L67	1550	L66 and L62	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L68	113	"382"/\$.ccls. and L67	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L69	343	"356"/\$.ccls. and L67	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L70	252	"250"/\$.ccls. and L67	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L71	35	("4751376").URPN.	USPAT	OR	ON	2006/01/17 16:47
L72	165	L54 and L60	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L73	1093777	switch or switching or shutter or shuttering	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L74	44	L72 and L73	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L75	5	((("6078392") or ("6262818") or ("5572598") or ("5583639") or ("5471303"))).PN.	US-PGPUB; USPAT	OR	OFF	2006/01/17 16:47
L76	4275	complex with phase with amplitude	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L77	1563	L60 and L76	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L78	1040	L66 and L77	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L79	12	L54 and L78	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L80	80083	interfer or interfere or interfering or interference or interferometer or interferometric or interferometrically or interferogram	EPO; JPO; IBM_TDB	OR	ON	2006/01/17 16:47
L81	1259961	image or imaging or imager	EPO; JPO; IBM_TDB	OR	ON	2006/01/17 16:47
L82	25543	microscope or microscopic or microscopically	EPO; JPO; IBM_TDB	OR	ON	2006/01/17 16:47
L83	1028586	semiconductor or wafer or substrate or mask or die or reticle	EPO; JPO; IBM_TDB	OR	ON	2006/01/17 16:47
L84	85807	align or aligning or aligner or alignment	EPO; JPO; IBM_TDB	OR	ON	2006/01/17 16:47
L85	647982	detector or sensor or "ccd"	EPO; JPO; IBM_TDB	OR	ON	2006/01/17 16:47
L86	24632	magnify or magnification or magnifying	EPO; JPO; IBM_TDB	OR	ON	2006/01/17 16:47

L87	638384	switch or switching or shutter or shuttering	EPO; JPO; IBM_TDB	OR	ON	2006/01/17 16:47
L88	237	complex with phase with amplitude	EPO; JPO; IBM_TDB	OR	ON	2006/01/17 16:47
L89	12103	L80 and L81	EPO; JPO; IBM_TDB	OR	ON	2006/01/17 16:47
L90	407	L89 and L84	EPO; JPO; IBM_TDB	OR	ON	2006/01/17 16:47
L91	147	L89 and L86	EPO; JPO; IBM_TDB	OR	ON	2006/01/17 16:47
L92	798	L89 and L87	EPO; JPO; IBM_TDB	OR	ON	2006/01/17 16:47
L93	0	L90 and L88	EPO; JPO; IBM_TDB	OR	ON	2006/01/17 16:47
L94	0	L91 and L88	EPO; JPO; IBM_TDB	OR	ON	2006/01/17 16:47
L95	0	L92 and L88	EPO; JPO; IBM_TDB	OR	ON	2006/01/17 16:47
L96	29	L90 and L82	EPO; JPO; IBM_TDB	OR	ON	2006/01/17 16:47
L97	13	L92 and L82	EPO; JPO; IBM_TDB	OR	ON	2006/01/17 16:47
L98	33	L91 and L82	EPO; JPO; IBM_TDB	OR	ON	2006/01/17 16:47
L99	34	linnik	EPO; JPO; IBM_TDB	OR	ON	2006/01/17 16:47
L100	193	(356/479).CCLS.	US-PGPUB; USPAT	OR	OFF	2006/01/17 16:47
L101	229	(356/497).CCLS.	US-PGPUB; USPAT	OR	OFF	2006/01/17 16:47
L102	1	("5112129").PN.	US-PGPUB; USPAT	OR	OFF	2006/01/17 16:47
L103	503018	wave or wavefront	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L104	703980	interfer or interfere or interfering or interference or interferometer or interferometric or interferometrically or interferogram	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L105	825294	image or imaging or imager	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L106	879040	complex or imaginary	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L107	4275	complex with phase with amplitude	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L108	4711	(complex or imaginary) with phase with amplitude	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47

L109	1738	L105 and L108	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L110	326670	defect or imperfection or flaw	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L111	1134	L104 and L109	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L112	244	L111 and L110	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L113	22	"250"/\$.ccls. and L112	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L114	936222	semiconductor or wafer or die or reticle or mask	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L115	50989	L110 same L114	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L116	60	L111 and L115	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L117	55	"356"/\$.ccls. and L112	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L118	59	L116 and L103	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L119	204	L112 and L103	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L120	326670	defect or imperfection or flaw	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L121	4711	(complex or imaginary) with phase with amplitude	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L122	41965	(complex or imaginary) with (phase or amplitude)	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L123	825294	image or imaging or imager	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L124	503018	wave or wavefront	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L125	1187085	L123 or L124	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L126	326670	defect or imperfection or flaw	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L127	703980	interfer or interfere or interfering or interference or interferometer or interferometric or interferometrically or interferogram	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L128	879040	complex or imaginary	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L129	825294	image or imaging or imager	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L130	503018	wave or wavefront	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47

L131	1187085	L129 or L130	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L132	296150	L128 and L131	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L133	94434	L127 and L132	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L134	21796	L133 and L126	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L135	1325114	semiconductor or wafer or substrate or mask or die or reticle	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L136	17847	L134 and L135	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L137	51871	"356"/\$.ccls.	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L138	794	L137 and L136	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L139	7155	"356"/450-521.ccls.	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L140	1027	L139 and L126	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L141	204	L139 and L136	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L142	703980	interfer or interfere or interfering or interference or interferometer or interferometric or interferometrically or interferogram	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L143	326670	defect or imperfection or flaw	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L144	879040	complex or imaginary	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L145	825294	image or imaging or imager	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L146	503018	wave or wavefront	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L147	1325114	semiconductor or wafer or substrate or mask or die or reticle	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L148	1187085	L145 or L146	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L149	73391	L142 same L148	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L150	2651	L149 same L144	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L151	70492	L148 same L144	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47
L152	51	L150 same L143	US-PGPUB; USPAT	OR	ON	2006/01/17 16:47

L153	50	("4818110").URPN.	USPAT	OR	ON	2006/01/17 16:47
L154	58	("5112129").URPN.	USPAT	OR	ON	2006/01/17 16:47
L155	1	("6873354").PN.	US-PGPUB; USPAT	OR	OFF	2006/01/17 16:47
L156	0	("6873354").URPN.	USPAT	OR	ON	2006/01/17 16:47
L157	1	"6078392".PN.	USPAT; USOCR	OR	ON	2006/01/17 16:47
L158	1	"5808735".PN.	USPAT; USOCR	OR	ON	2006/01/17 16:47
L159	33	("5808735").URPN.	USPAT	OR	ON	2006/01/17 16:47
L160	1	"5553157".PN.	USPAT; USOCR	OR	ON	2006/01/17 16:47
L161	1	"5479257".PN.	USPAT; USOCR	OR	ON	2006/01/17 16:47
L162	1	"4768881".PN.	USPAT; USOCR	OR	ON	2006/01/17 16:47
L163	1	"5295200".PN.	USPAT; USOCR	OR	ON	2006/01/17 16:47
L164	1	"3697149".PN.	USPAT; USOCR	OR	ON	2006/01/17 16:47
L165	1	("6075880").PN.	US-PGPUB; USPAT	OR	OFF	2006/01/17 16:47
L166	3	("6075880").URPN.	USPAT	OR	ON	2006/01/17 16:47
L167	1	("5112129").PN.	US-PGPUB; USPAT	OR	OFF	2006/01/17 16:47
L168	1	("6480285").PN.	US-PGPUB; USPAT	OR	OFF	2006/01/17 16:47
L169	18946	(interfer or interfere or interfering or interference or interferometer or interferometric or interferometrically or interferogram).clm.	US-PGPUB	OR	ON	2006/01/17 16:59
L170	98573	(image or imaging or imager).clm.	US-PGPUB	OR	ON	2006/01/17 17:00
L171	37794	(align or aligning or aligner or alignment).clm.	US-PGPUB	OR	ON	2006/01/17 17:00
L172	173565	(semiconductor or wafer or substrate or mask or die or reticle).clm.	US-PGPUB	OR	ON	2006/01/17 17:02
L173	1998	169 and 170	US-PGPUB	OR	ON	2006/01/17 17:03
L174	236	173 and 171	US-PGPUB	OR	ON	2006/01/17 17:03
L175	118	172 and 174	US-PGPUB	OR	ON	2006/01/17 17:03
L176	4253	(microscope or microscopic or microscopically).clm.	US-PGPUB	OR	ON	2006/01/17 17:04
L177	12	175 and 176	US-PGPUB	OR	ON	2006/01/17 17:04